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TABLE OF CONTENTS

LDO Comparison with New Push-Pulled Flipped Voltage Follower Topology for Transient Response Improvement 1
Jimmy Fort, Clement Champeix, Nicolas Borrel

Benchmarking and Validation of Sub-MW 30GHz VG-LNAs in 22nm FDSOI CMOS for 5G/6G Phased-Array Receivers 6
Domenico Zito, Michele Spasaro

Structure for Characterization of MOS Transistors in 28FD-SOI Technology 11
Jérémy Bonnet, Stéphane Meillere, Fabien Granoux, Wenceslas Rahajandraibe

Enhancing Automotive Embedded Applications: A Comprehensive Evaluation of Control Flow Checking Methods 16
Mohammadreza Amel Solouki, Jacopo Sini, Massimo Violante

Design and Characterization of an Integrated Multi-Sensor Device for Air Quality Monitoring 22
Pellegrino Jonas, Aziza Hassen, Guerin Mathieu, Taranto Pascal

Embedded Feature Selection in MCU Performance Screening 28
Nicolò Bellarmino, Riccardo Cantoro, Martin Huch, Tobias Kilian, Ulf Schlichtmann, Giovanni Squillero

IR-UWB Synthesizer Based on a Non-Uniformly Sampled Envelope for High Side-Lobes Rejection 34
F. A. Schoulten, R. Vauche, J. Gaubert, S. Bourdel, A. A. Mariano

MOSFET Electron Mobility Enhancement Using Source/Drain Recess 38
L. Antunes, P. Devoge, P. Masson, J. Amouroux, J. Dura, C. Rivero, F. Julien

Optimization of senseFET for Current Sensing in Low Voltage Power Integrated Systems 42
Marina Ruggeri, Patrick Calenzo, Frédéric Morancho, Lia Masoero, Rosalia Germana

LC-VCO Design with Switched Varactor Array for L-Band in 65 nm CMOS Technology 48
Agord M. Pinto, Raphael R. N. Souza, Jorge E. V. Solano, Eduardo R. De Lima, Leandro T. Manera

Power Consumption Reduction in Integrated Pacemakers: Design Strategies for Cortex-M0+ Processors 54
Wafa Zitouni, Rémy Vauche, Hassen Aziza, Laila Ayache, Alaa Makdissi

Cancelation of Successive Low-Rank Harmonics and Homopolar Voltage, by Using Pulse Width and Height Modulation (PWHM) in a New Topology of Three-Phase Six-Level Inverter 60
Bile Mohamed Bile, Abderrezzak Pr Cherifi, Kamal Meghriche, Hassan Ali Barkad, Riad Djebarra

Experimental Study of Force Induced by Probe Length Influence on Electrical Contact Resistance of Pillar Bump-Flat Vertical Probe Interaction During Wafer Electrical Test 66
Cedric Hermet, Luc Favre, Stéphanie Escoubas, Salvatore De Siena, Robert Diperi

OpenTRNG: An Open-Source Initiative for Ring-Oscillator Based TRNGs 72
Florian Pebay-Peyroula, Licinius-Pompiliu Benea, Mikael Carmona, Romain Wacquez

Punch-Through Variability in Buried Channel Transistors 78
C. Belabbas, S. Perrin, R. Habhab, V. Della Marca, P. Masson, P. Canet, J-M. Portal, T. Kempf, N. Miridi, M. Mantelli, S. Niel, A. Regnier

IJTAG-Compatible Symptom-Based SEU Monitors for FPGA DNN Accelerators 83
Natalia Cherezova, Maksim Jenihhin, Artur Jutman

Producing a Bidirectional ATPG Compliant Verilog-HDL Memory Model of SRAM 89
D. Ronga, X. Xhafa, E. Faehn, P. Girard, T. Vayssade, A. Virazel

Machine Learning-Based Feasibility Estimation of Digital Blocks in BCD Technology 95
Francesco Daghero, Gabriele Faraone, Michelangelo Grosso, Daniele Jahier Pagliari, Nicola Di Carolo, Giovanna Antonella Franchino, Dario Licastro, Eugenio Serianni

LC-VCO with 1.6 GHz Tuning Range and Switched Cross-Coupled Core for Power Optimizing 101
Raphael R. N. Souza, Agord M. Pinto, Roberto L. De Orio, Leandro T. Manêra, Eduardo R. De Lima

A 6-Bit Low-Area Hybrid ADC Design for System-On-Chip Measurements 107
Nima Kolahimahmoudi, Giorgio Insinga, Stefano Roggi, Josef Niederl, Paolo Bernardi

Investigation on the Design of LP-NGD Analog System with RL-Network 113
Mathieu Guerin, Fayrouz Haddad, Wenceslas Rahajandraibe, Blaise Ravelo

Detection and Estimation of Ethanol Concentration in a Disturbed Environment Utilizing Random Forest 118
Ndricim Ferko, Mohand. A. Djeziri, Hiba Al Sheikh, Nazih Moubayed, Marc Bendahan, Jean-Luc Seguin

Optimization of Digital Transistors for Low-Cost and Low-Power IoT Applications in 40nm Technology 123
Noemie Couzi, Jeremy Postel-Pellerin, Hassen Aziza, Alexandre Malherbe, Abderrezak Marzaki, Stephan Niel

Voltage-Controlled Ring Oscillator with Reliability Criterion for Radiation Effects 129
Agord De Matos Pinto Júnior, Raphael Ronald Noal Souza, Eduardo Rodrigues De Lima, Cassia Maria Chagas, Leandro Tiago Manêra

Evaluation of Human Body Communications Pathloss Using Capacitive Coupling 135
S. Al Zaouk, R. Assila Belhadj Mefteh, R. Vauché, R. Abdeddaim, N. Dehaese, M. Guerin

Three-Phase Inverter Without PWM for On-Board Actuator 139
Ahmed Hassan Abdoul-Aziz, Cherifi Abderrezzak, Hadri Ferhat, Ali Barkad Hassan

Design Enhancement of Folded Beams Attachment for MEMS-Based Triaxial Accelerometer 145
Fatma Khayat, Dorra Nasr, Mohamed Hadj Said, Mounir Mansour, Fares Tounsi

How Systolic Array Dataflow Impacts on the Resilience to Hardware Faults 151
Salvatore Pappalardo, Bastien Deveautour, Alberto Bosio

Fast Exploration of the Impact of Precision Reduction on Spiking Neural Networks 157
Sepide Saeedi, Alessio Carpegna, Alessandro Savino, Stefano Di Carlo

Reliable and Efficient Hardware for Trustworthy Deep Neural Networks 163
Salvatore Pappalardo, Ali Piri, Annachiara Ruospo, Bastien Deveautour, Ernesto Sanchez, Alberto Bosio

AI Eye Charts: Measuring the Visual Acuity of Neural Networks with Test Images 168
Antonio Porsia, Annachiara Ruospo, Ernesto Sanchez

Combining Acceleration and Approximation in Dependable Edge AI: Optimization Methodology and Tools Applied to a Case Study 173
Régis Leveugle, Mounir Benabdenbi, Ahmed Al Kaf, Luc Noizette

Fault Tolerant Design for Memristor-Based AI Accelerators 179
Theofilos Spyrou, Artemis Zografou, Said Hamdioui, Anteneh Gebregiorgis

Testing ReRAM-Based TCAM for Computation-In-Memory Applications 183
Haneen G. Hezayyin, Mahta Mayahinia, Mehdi Tahoori

Lifecycle Management of RRAMs: Quality and Reliability 187
Leticia Maria Bolzani Pöhls

Extreme Temperature Automotive Testing 191
Ben Lok, Si Diep, Thomas Pham, Nicholas Madrid, Mit Shah, Andrew Westall, Hamzeh Dessouki, Linh Truong, Andrew Davis

Testing Challenges Along WBG and UWBG Devices Roadmap 199
Elena Venuti, Davide Appello, Riccardo Vettori, Federico Fazio, Rosalia Biondi, Chiara Lauria, Tiziana Bertoncelli, Giancarlo Guida, Marco Occhiali

Author Index